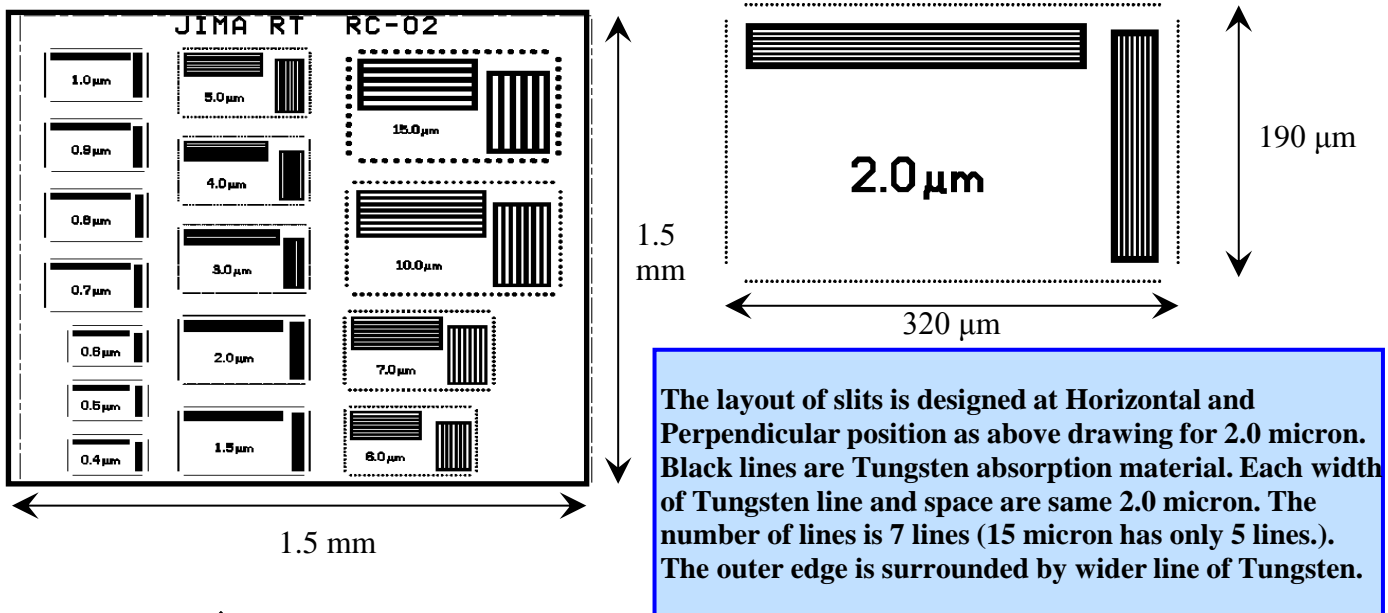


Micro Resolution Chart for X-Ray

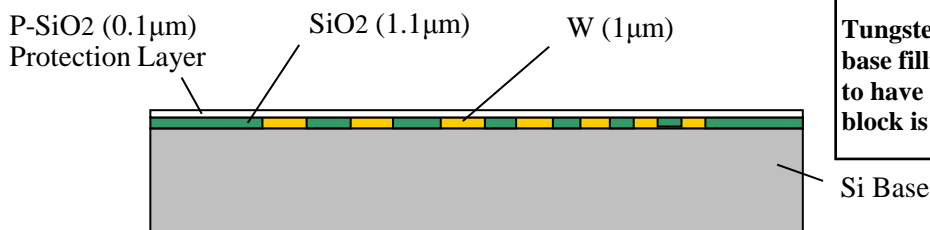
JIMA RT RC-02B

Micro-focus type of X-ray inspection systems are currently in common use. The micro-chart is most indispensable to adjust focus-point (size / shape) for X-ray images. In genera, it is necessary to maintain the capability of X-ray systems . This micro-chart has been fabricated by using the latest semiconductor lithography techniques. As the result, sub-micron slits down to 0.4 micron could be achieve. (0.4, 0.5, 0.6, 0.7, 0.8, 0.9, 1.0, 1.5, 2.0, 3.0, 4.0, 5.0, 6.0, 7.0, 10.0, 15.0 μm , 16 different width) JIMA (Japan Inspection Instruments Manufacturers' Association) has succeeded to supply with an economical price by quantity produce.

Line and Space Pattern



Cross Section (Si Base thickness: 60 micron)



Tungsten chart is drawn on 5 mm square Si base filling the gap with SiO₂, then polished to have nearly 1 micron thickness. And Si block is fixed on 30x40 mm Aluminum plate.

Specification

1. Whole Size: 40x30x5 mm
2. Si Plate: 5x5x0.06 mm
3. Absorption Material: Tungsten (W) 1.0 μm Thickness
4. Protection Film: Pycarbonate 0.1 mm Thickness
5. Tolerance of Slit width and space: +/- 10% or less under 2 μm , +/- 8% or less over 3 μm (At 23 degree C)
6. Slit Width: 0.4, 0.5, 0.6, 0.7, 0.8, 0.9, 1.0, 1.5, 2.0, 3.0, 4.0, 5.0, 6.0, 7.0, 10.0, 15.0 μm , 16 size
7. Number of Slit: 7 (Only 15 μm : 5)
8. Protection Case included
Micro-Chart, Certification, Operation Manual
9. Operation Temperature Range: 10 $^{\circ}\text{C}$ to 70 $^{\circ}\text{C}$

NOTE:
RC-02B has same chip as RC-02, but has modified aluminum base plate.



JIMA RT RC-02B

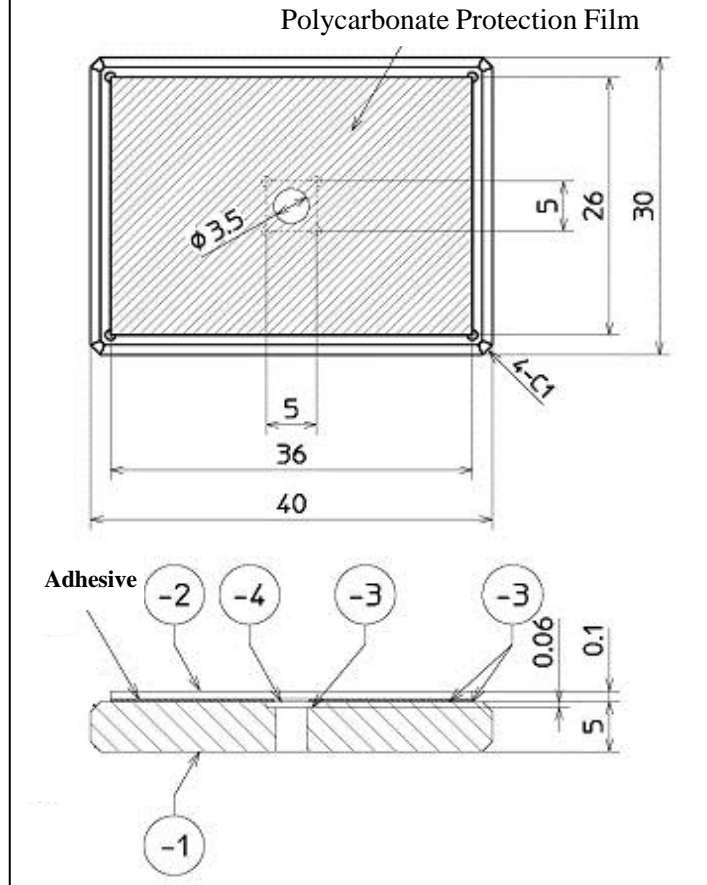
Micro-Chart (Reversed side)



Protection Case



Outer Drawing (Top side)



No.	Parts	Material	Size(mm)
-1	Aluminum Plate	A2017P	40x30x5
-2	Protection Film	Polycarbonate	36x26x0.1
-3	Adhesive Material	Silicon	included above
-4	Silicon Base	S	5x5x0.06
	Absorption Material	W	t=1.0μm